		Application/Control No.	A	pplicant(s)/Pate	Applicant(s)/Patent under Reexamination	tion
Issue Classification	ion	09116124	Z	NISHINA ET AL.		
		Examiner Tran, Hai	A ~	Art Unit		
IO	ORIGINAL		INTERN	IATIONAL C	INTERNATIONAL CLASSIFICATION	z
CLASS		SUBCLASS	CLAIMED		NON-CLAIMED	AIMED
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CROSS R	CROSS REFERENCE(S)	(S)				
CLASS SUBCLAS	SUBCLASS (ONE SUBCLASS	ASS PER BLOCK)				
725 39	47	49				
NONE (Assistant Examiner)	(Date)	HAITBAN PHINTRY CEXAMINER	PAN		Total Claims Allowed:	Allowed:
(Legal Instruments Examiner)	10/16/06 (Date)	Hai V. Tran (Primary Examiner)	10/16/2006 (Date)		O.G. Print Claim(s) 1	O.G. Print Figure 4

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